Minimizing Noise and Bias in 3D DIC

Correlated Solutions, Inc.

Overview

- Overview of Noise and Bias
- Digital Image Correlation Background/Tracking Function
- Minimizing Noise
	- Focus
	- Contrast/Lighting
	- Glare
	- F-stop
	- Stereo-Angle/Lens selection
	- **Good speckle pattern**

▫ Eliminating Bias

- Eliminating aliasing
- Eliminating contaminations/dust
- Using a our Distortion Correction module for instances of non-parametric distortions, such as the stereomicroscope.

Overview of Noise and Bias

- Noise: random, zero-mean deviations from the correct result
- Bias: systematic deviations from the correct result
- Noise and bias are present for location (inplane, out-of-plane), displacement, and strain
- Noise is unavoidable, but can be minimized with careful setup
- Bias can be reduced or eliminated with proper setup and parameters

Minimizing Noise:

- Accuracy can be very variable. Some amount of noise will always be present, but it is possible to minimize noise by paying attention to the following set-up parameters:
	- Focus
	- Contrast/Lighting
	- Glare
	- F-stop
	- □ Stereo-Angle/Lens selection
- Once we have the proper set-up, **speckle pattern quality** is the **most** important factor for minimizing noise

Eliminating Bias:

- Eliminating aliasing
- Eliminating contaminations/dust
- Using a our Distortion Correction module for instances of non-parametric distortions, such as the stereo-microscope.

DIC background

To understand noise and accuracy is presented in DIC, it's essential to understand how we track the specimen

- We track the specimen by assigning subsets throughout the area of interest that contain unique speckle information.
- We track where these subsets move by checking for possible matches at several locations and use a similarity score (correlation function) to grade them. The march is where the error function is minimized.
- **Classic correlation function**: sum of squared differences (SSD) of the pixel values (smaller values = better similarity)

- **Example**
	- **White pixels** are gray level **100**
	- **Black pixels** are gray level **0**
- An image is a matrix of natural integers

- **Example**
	- The **specimen moves** such that **its image moves 1 pixel up and right**

▫ Example: subset at **(x;y)=(5;5),** displacement candidate **(u;v)=(-2;-2)**

$$
C(5,5,-2,-2) = \sum_{i,j=-2}^{2} (I(5+i,6+j) - I^*(5-2+i,5-2+j))^2
$$

 $(100-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (100-0)^2 = 18,000$ $(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 +$ $(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 +$ $(0-100)^2 + (0-100)^2 + (0-100)^2 + (0-100)^2 + (0-0)^2 +$ $(100-0)^2 + (0-0)^2 + (0-0)^2 + (0-0)^2 + (100-0)^2 +$

- Example: subset at **(x;y)=(5;5),** displacement candidate **(u;v)=(1;1)** $C(5,5,1,1) = 0$
- Better correlation score than candidate (u;v)=(-2;-2) [18,000] Indeed it is the smallest score achieveable (perfect match)

Noise Reduction

■ How do we reduce displacement noise?

$$
Var = \frac{2\sigma^2}{\sum (\partial G/\partial x)^2}
$$

- Reduce camera noise
	- Limited options!
- Increase subset size
	- Loss of spatial resolution
- Optimize speckle pattern and test setup ▫ This is our best and most important option

Iteratively finding the match

Shape of error curve

▫ We optimize for U, V, strain, and rotation □ Let us consider the 1D case - U only

Error

U-position

Shape of error curve

▫ Typical pattern

Noise in error curve

Effects of noise

- Noise normally **cannot** be controlled
- We must increase the **signal**
- Steeper drop = better confidence

What do we want in a pattern?

How do we make the bowl deep?

▫ Good contrast

▫ Good speckle size

How do we make the bowl narrow?

- Sharp edges
- Good focus
- Proper F-stop

Great pattern example

Great pattern example

- Sharpie marker on white paint
- Bright whites
- Dark blacks
- □ Hard edges
- Consistent speckle size

High-contrast printed pattern

High-contrast printed pattern

- Laser printer
- CSI target generator
- Good contrast
- Consistent size

A typical painted pattern

A typical painted pattern

- Inconsistent size
- No bright white areas
- Soft edges

Effect of reduced contrast

Other considerations

- Focus
- Brightness
- Glare
- F-stop

Effect of reduced focus

Aperture too small

Effect of low light

Effect of too much light

- Aliasing occurs when a signal isn't sampled frequently enough to represent it.
- Aliasing in a 1D signal:

▫ Aliasing occurs when the scene contains high-frequency content that cannot be represented by the pixel resolution of the image

- Aliasing is dangerous because it **does not always** appear in the "sigma" value
- We can sometimes see aliasing in the result

▫ This is both a bias and an accuracy problem even when not apparent!

▫ Overly fine pattern

▫ Showing translation

Displacement error from aliasing

- We calculate the **actual** displacement vs. the local **measured** displacement
- The error is plotted vs. position

Displacement error from aliasing

Strain error from aliasing

- □ This can cause very serious strain errors!
- Waves of compressive strain and tensile strain cause ripples

▫ Low fill factors can exacerbate the aliasing issue for a given pattern

Bias Due to Aliasing

▫ An example of an extremely aliased image – due to dithering from a laser printer

▫ An example of an extremely aliased image – due to dithering from a laser printer

▫ Aliased shape

▫ With low-pass filtering of image

Effects of Aliasing

▫ Greatly reduces aliasing - at the expense of actual accuracy

Effects of Aliasing

▫ Use of low pass filter can help

- Aliasing can cause severe biases and noise in displacement and strain
- Best to avoid in the first place bigger patterns or more magnification
- Can be mitigated
	- Low-pass image filter
		- This comes at the expense of resolution
	- Higher order interpolation

A better pattern

▫ Showing translation

A better pattern

▫ Stronger pattern – aliasing still visible (low quality camera) but much weaker

Mixed sizes - synthetic

Mixed sizes - real

Speckle Pattern Conclusions

▫ Why is this important?

Conclusions

▫ Z-accuracy

Speckle Pattern Conclusions

▫ False strain (300uε vs 1300uε)

Speckle Pattern Conclusions

0.0031

- 3D image correlation contains another important step
- We want to minimize our Sigma_X/Y/Z
	- This will minimize our strain noise
	- Two components
		- Low pixel sigma
		- Proper test setup

Camera pinhole point

 \bullet

Optical axis

Camera pinhole point

- By taking the set of all possible points, we generate a 3D volume in space.
- The volume has a height (Sigma_Y), a width (Sigma_X), and a depth (Sigma_Z)

- How to minimize the error volume?
	- Minimize noise

Effects of setup

Short focal length; small angle

Effects of setup

Short focal length; large angle
Effects of setup

Long focal length; large angle

Minimizing Bias & Noise

▫ Noise in displacement and strain is strongly dependent on stereo angle

Minimizing Bias & Noise

▫ Noise is lowest near the optical axis

Bias Due to Contaminations

▫ Contamination can cause severe biases in displacement (u shown):

▫ This bias will have a strong effect on calculated strains (exx shown):

Bias Due to Contaminations

- Contaminations (e.g., dust on sensor) cause large localized bias in displacement estimates
- Typically, a large erroneous strain concentration results
- Not possible to mitigate through processing techniques
- Always check before taking measurements

Bias Due to Poor Calibration

- □ A low calibration score is indicative of a good calibration IF we have enough information in the calibration images
	- Large grid that fills up entire image
	- Very large grid tilts (tilt it until it starts to go out of focus)
	- 15-25 calibration image sets
- □ If using short focal length lenses (8mm, 12mm), you might need to change the distortion order to 2 or 3 in the distortion window.
- In high magnification applications, you might need to select "High Mag" in the calibration window.

Bias Due to Poor Calibration

▫ Distortion order for short lenses

- Calibrate at distortion order 1. Look at your kappa 1 (a lens distortion parameter) in your calibration results.
- Calibrate at distortion order 2. You'll have a kappa 2 now, but if your kappa 1 is the same as what you got for a distortion order of 1, then the distortion order of 1 was OK.
- If the kappa 1 changed, then repeat for an order of 3 and see if kappa 2 changed.
- Once you figure out the distortion order, you can use that that order anytime you use that camera-lens combination

Bias Due to Poor Calibration

- High Magnification
	- For high magnification instances you might see very large calibration errors.
	- This is because the limited depth of field doesn't allow us to tilt the grid enough in order to extract the camera sensor positions.
	- Check your center x, center y for each camera in your calibration results
	- □ The centers should be ROUGHLY the centers of the sensors (i.e. for 5MP cameras that are 2448x2048 pixels, you should see centers of 1224,1024)
	- □ If centers are WAY off (by more than 50%; maybe even negative), select "high mag"
	- This will force the centers to the center of the sensor (1224x1024 in this case).
	- Only use the high mag option when completely necessary because it forces the software to make some assumptions that we'd rather extract from the calibration image.
	- "High mag" is not an option for the stereo microscope module; we use a different calibration method (see next slides)

- For simple lenses the calibration error is typically not a concern when using proper calibration techniques
- For complex optics, such as the stereo microscope, parametric distortion models are typically not sufficient and severe bias results
- For accurate measurements using stereo microscopes (or SEMs), a non-parametric distortion calibration technique is required
- DIC can be used to calibrate such distortions using a simple motion constraint scheme

▫ Uncorrected shape for a flat plate

▫ Corrected shape for a flat plate

▫ Uncorrected strain for rigid motion

Bias Elimination

▫ Corrected strain for rigid motion

Conclusions

- With proper set-up, we can eliminate bias and minimize noise.
- Front-end reductions
	- Proper test setup (focal length, stereo angle, clean lens/sensor, good lighting, correct F-stop, well focused, no blur, no glare)
	- Good speckle pattern (consistent speckle pattern, 50% coverage, good contrast, sharp speckle edges)
	- Good calibration (good tilt in calibration images, select high magnification or distortion order if necessary)

■ Back-end reductions

- Correct subset sizes
- Low-pass filtering, if necessary
- Distortion correction for stereo microscope applications